



10-15-04

file 1763

CERTIFICATE OF EXPRESS MAIL	
Express Mail Tracking No.:	EV 468040975 US
Date of Deposit:	October 14, 2004
I hereby certify that this paper or fee is being deposited with the United States Postal Service "EXPRESS MAIL POST OFFICE TO ADDRESSEE" service under 37 C.F.R. 1.10 on the date indicated above and is addressed to: Commissioner for Patents, PO Box 1450, Alexandria VA, 22313-1450.	
Rebecca R. Ginn	

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of:  
David Becker et al.

Serial No.: 09/923,058

Filed: 8/6/01

For: METHODS FOR ENHANCING SILICON  
DIOXIDE TO SILICON NITRIDE  
SELECTIVITY (*as previously amended*)

Group Art Unit: 1763

Examiner: George Goudreau

Examiner phone: 571-272-1434

Atty. Dkt. No.: 102-0072US-4

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria VA, 22313-1450

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, it is respectfully requested that this Information Disclosure Statement (IDS) be entered and the documents listed on attached Form PTO-1449 be considered by the Examiner and made of record. Copies of the listed documents are attached.

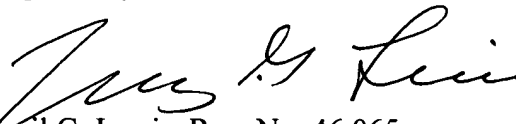
In accordance with 37 C.F.R. §§ 1.97(g),(h), this IDS is not to be construed as a representation that a search has been made, and is not to be construed to be an admission that the information cited is, or is considered to be, material to patentability as defined in 37 C.F.R. § 1.56(b), or that such information constitutes prior art.

As these references were not submitted with the Applicant's most recent IDS, the numbering of the listed references on the attached Form 1449 continues from the numbering used in the Information Disclosure Statement previously submitted on June 10, 2004.

This IDS is being filed after a first office action on the merits, but before the close of prosecution. Accordingly, a fee of \$180.00 is believed due. ***This Office is authorized to deduct this fee, and any other necessary fees, from Deposit Account No. 501922, referencing matter no. 102-0072US-4.***

Applicant respectfully requests that the listed documents be considered and made of record in the present case, and that the Examiner initial the appropriate spaces on the Form 1449 to evidence the same.

Respectfully submitted,



Terril G. Lewis, Reg. No. 46,065

Wong, Cabello, Lutsch, Rutherford  
& Brucculeri, LLP  
20333 SH 249  
Houston, Texas 77070  
(832) 446-2422  
Fax: 832 446-2424

Oct. 14, 2004

Form PTO-1449 (modified)

Atty. Docket No.  
102-0072US-4Serial No.  
09/923,058

List of Patents and Publications for Applicant's

INFORMATION DISCLOSURE STATEMENT

Inventor/Applicant:

Becker, et al. / Micron Technology, Inc.

Title: METHODS FOR ENHANCING SILICON  
DIOXIDE TO SILICON NITRIDE  
SELECTIVITY (as previously amended)

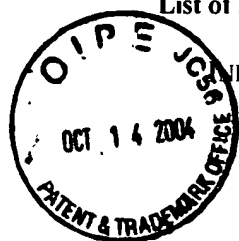
Filing Date:

08/06/01

Group:

1763

(Use several sheets if necessary)



## U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.
	A82	3,653,898	4/4/72	Shaw	96	35	
	A83	3,904,454	9/9/75	Magdo et al.	156	11	
	A84	4,135,954	1/23/79	Chang et al.	148	187	
	A85	4,243,435	1/6/81	Barile et al.	148	1.5	
	A86	4,696,097	9/29/87	McLaughlin et al.	437	193	
	A87	4,832,789	5/23/89	Cochran et al.	156	644	
	A88	4,837,176	6/6/89	Zdebel et al.	437	31	
	A89	4,030,967	6/21/77	Ingrey et al.	156	643	
	A90	4,671,849	6/9/87	Chen et al.	156	643	
	A91	5,312,518	5/17/94	Kadomura	156	662	5/29/92
	A92	6,399,514	6/4/02	Marks et al.	438	729	8/24/00
	A93	4,883,767	11/28/89	Gray et al.	437	41	
	A94	4,962,058	10/9/90	Cronin et al.	437	187	
	A95	5,136,124	8/4/92	Cronin et al.	174	261	9/19/1990
	A96	5,169,802	12/8/92	Yeh	437	195	6/17/91
	A97	5,189,506	2/23/93	Cronin et al.	257	752	6/3/92
	A98	5,354,711	10/11/94	Heitzmann et al.	437	182	7/8/93
	A99	6,171,974	1/9/01	Marks et al.	438	740	1/24/92

## Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B	n/a					

EXAMINER:

DATE CONSIDERED:

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

Form PTO-1449 (modified)

Atty. Docket No.  
102-0072US-4Serial No.  
09/923,058

List of Patents and Publications for Applicant's

INFORMATION DISCLOSURE STATEMENT

Inventor/Applicant:

Becker, et al. / Micron Technology, Inc.

Title: METHODS FOR ENHANCING SILICON  
DIOXIDE TO SILICON NITRIDE  
SELECTIVITY (*as previously amended*)Filing Date:  
08/06/01Group:  
1763

(Use several sheets if necessary)

## Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
	C77	Various Japanese abstracts (untranslated) 8p-P-14, 8p-P-15, 8a-R-1
	C78	Various Japanese abstracts (untranslated) 7p-T-14, 7p-T-15, 7p-T-16
	C79	H. Enomoto & T. Tokunaga, "Analysis of Mechanisms of Highly Selective Oxide Etching," 1994 Dry Process Symposium, pp. 241-46 (Nov. 10-11, 1994, Tokyo).
	C80	Y. Gotoh & T. Kure, "Analysis of Polymer Formation During SiO <sub>2</sub> Microwave Plasma Etching," 1994 Dry Process Symposium, pp. 211-16 (Nov. 10-11, 1994, Tokyo).
	C81	Y. Hikosaka et al., "Inductively-Coupled Plasma Etching in a Pulsed Mode," 1994 Dry Process Symposium, pp. 199-204 (Nov. 10-11, 1994, Tokyo).
	C82	K. Kurihara et al., "Measurement of Energy Distribution of Ion Species Through a High-Aspect-Ratio Hole in a C4F8 Plasma," 1994 Dry Process Symposium, pp. 217-221 (Nov. 10-11, 1994, Tokyo).
	C83	Shin Arai, "Polymer Deposition Control in SiO <sub>2</sub> Etching by Substrate Temperature Manipulation," 1994 Dry Process Symposium, pp. 223-227 (Nov. 10-11, 1994, Tokyo).
	C84	Reply and Counterclaims in Reply to Counterclaim and Demand for Jury Trial, Motorola, Inc. v. Micron Technology, Inc., Civ. No. 04 CA 007 LY (Apr. 7, 2004) (W.D. Tex.).
	C85	J.L. Yeh et al., "Reverse Pillar—A Self-Aligned and Self-Planarised Metallisation Scheme for Sub-Micron Technology," Vacuum: Technology, Applications & Ion Physics, Vol. 38, Nos. 8-10, pp. 817-821 (1988).

EXAMINER:

DATE CONSIDERED:

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

